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Applicant(s): Yuen-Foo Michael Kou
METHOD AND APPARATUS FOR EVALUATING A SET OF
ELECTRONIC COMPONENTS

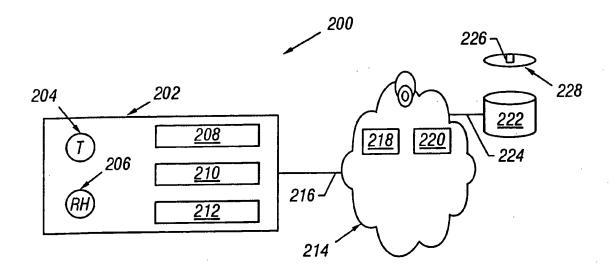


FIG. 2A

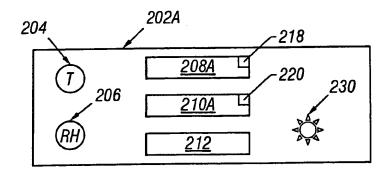


FIG. 2B



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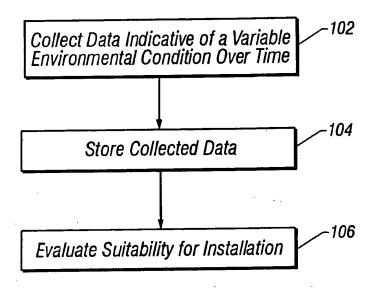


FIG. 1

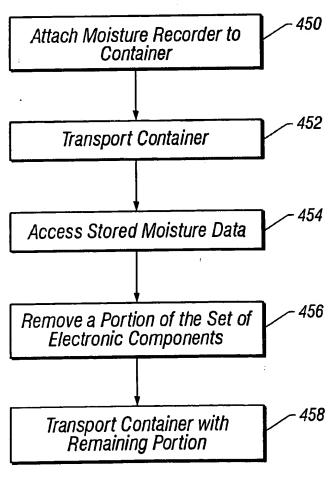


FIG. 4



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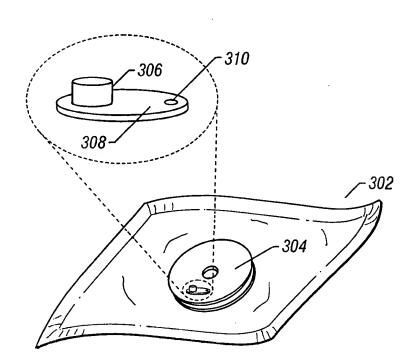


FIG. 3A



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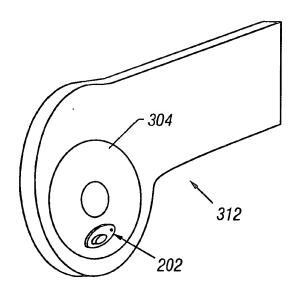


FIG. 3B

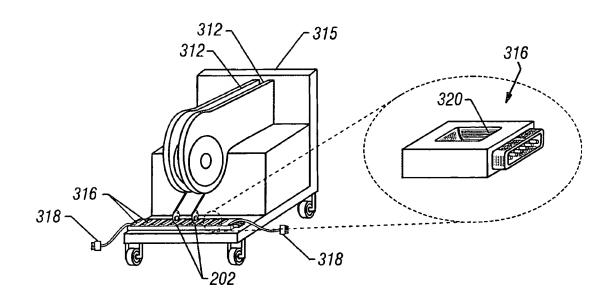


FIG. 3C



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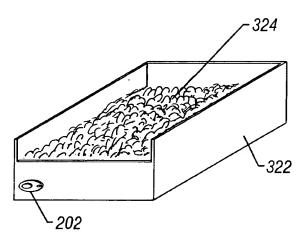


FIG. 3D

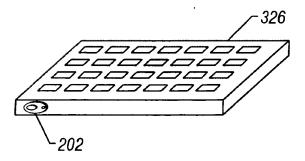


FIG. 3E

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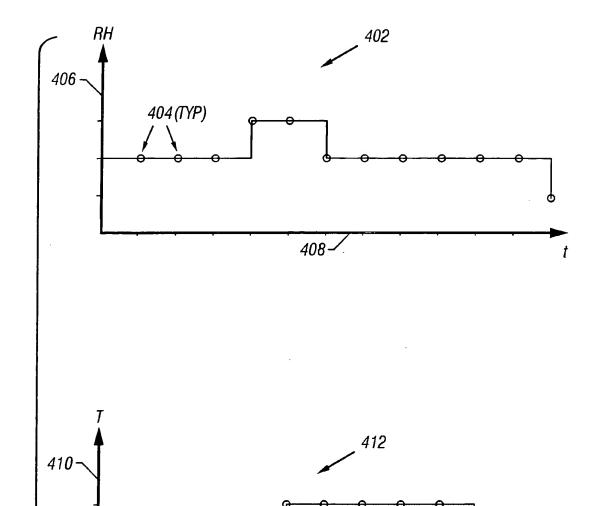
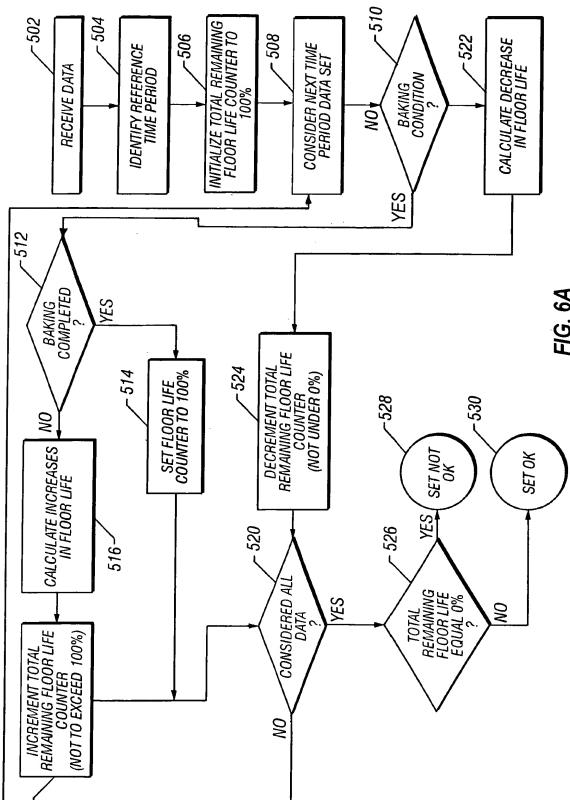


FIG. 5

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518.



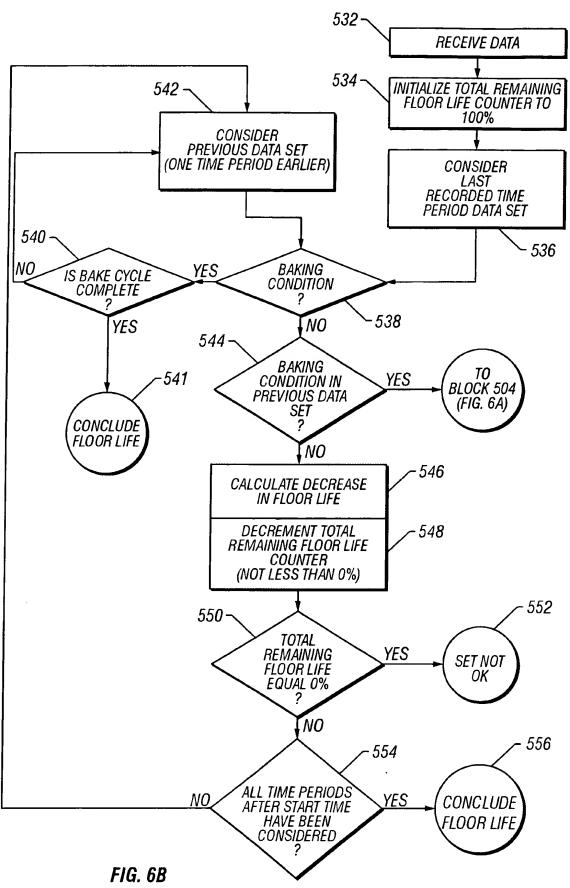
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April 1999

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TABLE 5 Recommended Equivalent Total Floor Life (days) @ 20°C,25°C & 30°C For ICs with Novolac, Biphenyl and Multifunctional Epoxies (Reflow at same temperature at which the component was classified)

	Maximum Dagant Dalatica Unividit									
0 / 7/1 / (1)	Maximum Percent Relative Humidity									
Body Thickness (t)	M.S.Level	20%	30%		├	60%	70%	80%	90%	<u> </u>
t>3.1mm PQFPs>84 pins. PLCCs (square) MQFPs or PBGAs	Level 2a	8 8 8	60 78 103	41 53 69	33 42 57	28 36 47	10 14 19	7 10 13	6 8 10	30°C 25°C 20°C
	Level 3	10 13 17	9 11 14	8 10 13	7 9 12	7 9 12	5 7 10	4 6 8	4 5 7	30°C 25°C 20°C
	Level 4	4 5 7	4 5 7	4 5 7	3 5 7	3 4 6	3 3 5	2 3 4	2 3 4	30°C 25°C 20°C
	Level 5	3 5 7	3 4 6	2 4 5	235	234	ಌಌಌ	123	123	30°C 25°C 20°C
	Level 5a	1 2 4	1 2 3	1 2 3	1 2 3	1 2 2	1 1 2	1 1 2	1 1 2	30°C 25°C 20°C
t≤2.1mm t<3.1mm PLCCs(rectangular)18-32 pins SOICs(wide body) SOICs≥20pins PQFPs≤80pins	Level 2a	888	888	86 148 œ	39 51 69	28 37 49	4 6 8	3 4 5	2 3 4	30°C 25°C 20°C
	Level 3	19 25 32	12 15 19	9 12 15	8 10 13	7 9 12	3 5 7	2 3 5	2 3 4	30°C 25°C 20°C
	Level 4	5 7 9	4 5 7	4 5 6	3 4 6	3 4 5	2 3 4	2 2 3	1 2 3	<i>30°C</i> 25°C 20°C
	Level 5	3 4 5	3 3 5	2 3 4	2 3 4	2 3 4	1 2 3	1 1 3	1 1 2	30°C 25°C 20°C
	Level 5a	1 2 2	1 2 2	1 2 2	1 2 2	1 2 2	1 1 2	0.5 1 2	0.5 1 1	30°C 25°C 20°C
t>2.1mm TSOPs, SOICs <18 pins TQFPs or or TBGAs	Level 2a	8 8 8	8 8 8	8 8 8	8 8 8	28 & &	1 2 2	1 1 2	1 1 1	30°C 25°C 20°C
	Level 3	8 8 8	8 8 8	8 8 8	11 14 20	7 10 13	1 2 2	1 1 2	1 1 1	30°C 25°C 20°C
	Level 4	888	9 12 17	5 7 9	4 5 7	3 4 6	1 2 2	1 1 2	1 1 1	30°C 25°C 20°C
	Level 5	13 18 26	5 6 8	3 4 6	2 3 5	2 3 4	1 2 2	1 1 2	1 1 1	30°C 25°C 20°C
	Level 5a	3 5 6	2 3 4	1 2 3	1 2 2	1 2 2	1 1 2	1 1 2	0.5 1 1	30°C 25°C 20°C

FIG. 7 (Prior Art)

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Package thickness	Level	Bake@125°C	Bake@40°c <u><</u> 5%RH
<u><</u> 1.4 mm	2a	4 hours	5 days
	3	7 hours	11 days
	4	9 hours	13 days
	5	10 hours	14 days
	5a	14 hours	19 days
<u><</u> 2.0 mm	2a	18 hours	21 days
	3	24 hours	33 days
	4	31 hours	43 days
	5	37 hours	52 days
	5a	48 hours	68 days
<u><</u> 4.0 mm	2a	48 hours	67 days
	3	48 hours	67 days
	4	48 hours	68 days
	5	48 hours	68 days
	5a	48 hours	68 days

Table 2 Reference Conditions for Drying Components that were Exposed to Conditions \leq 60% RH (User Bake:Floor Life Begins Counting at Time = 0 after bake)

FIG. 8 (Prior Art)

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